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- 3-State Inverting Outputs Drive Bus Lines Directly
- Full Parallel Access for Loading
- EPIC™ (Enhanced-Performance Implanted CMOS) 1-µm Process
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), Ceramic Chip Carriers (FK) and Flatpacks (W), and Standard Plastic (N) and Ceramic (J) DIPs

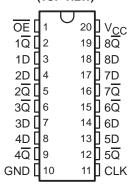
#### description

These octal edge-triggered D-type flip-flops feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. The devices are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

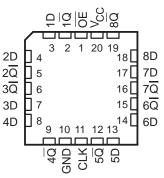
On the positive transition of the clock (CLK) input, the  $\overline{Q}$  outputs are set to the complements of the logic levels set up at the data (D) inputs.

A buffered output-enable  $(\overline{OE})$  input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state, the outputs

SN54AC534 . . . J OR W PACKAGE SN74AC534 . . . DB, DW, N, OR PW PACKAGE (TOP VIEW)



SN54AC534 . . . FK PACKAGE (TOP VIEW)



neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without need for interface or pullup components.

OE does not affect internal operations of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The SN54AC534 is characterized for operation over the full military temperature range of  $-55^{\circ}$ C to  $125^{\circ}$ C. The SN74AC534 is characterized for operation from  $-40^{\circ}$ C to  $85^{\circ}$ C.

### FUNCTION TABLE (each flip-flop)

	INPUTS		OUTPUT
OE	CLK	D	Q
L	1	Н	L
L	$\uparrow$	L	Н
L	H or L	Χ	$\overline{Q}_0$
Н	Х	Χ	Z



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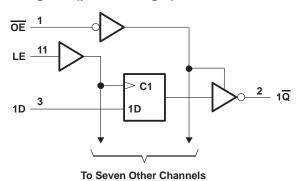


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#### logic symbol†

#### ΕN - C1 3 1D 1Q 1D 1⊳ 5 4 2Q 2D 7 6 3D 3Q 8 9 4D 4Q 12 13 5Q 5D 14 15 6Q 6D 17 16 7D 7Q 18 19 8D 8Q

#### logic diagram (positive logic)



### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V <sub>CC</sub>	–0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)	
Output voltage range, VO (see Note 1)	
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ )	±20 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0 or V <sub>O</sub> > V <sub>CC</sub> )	±20 mA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )	±50 mA
Continuous current through V <sub>CC</sub> or GND	±200 mA
Maximum power dissipation at $T_A = 55^{\circ}C$ (in still air) (see Note 2)	): DB package 0.6 W
	DW package 1.6 W
	N package 1.3 W
	PW package 0.7 W
Storage temperature range, T <sub>stg</sub>	–65°C to 150°C

<sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.



<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

<sup>2.</sup> The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils, except for the N package, which has a trace length of zero.

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### recommended operating conditions (see Note 3)

			SN54/	SN54AC534		C534	UNIT
			MIN	MAX	MIN	MAX	UNII
VCC	Supply voltage		2	6	2	6	V
		V <sub>CC</sub> = 3 V	2.1		2.1		
VIH	High-level input voltage	V <sub>CC</sub> = 4.5 V	3.15		3.15		V
		V <sub>CC</sub> = 5.5 V	3.85		3.85		
		V <sub>CC</sub> = 3 V		0.9		0.9	
V <sub>IL</sub>	Low-level input voltage	V <sub>CC</sub> = 4.5 V		1.35		1.35	V
		V <sub>CC</sub> = 5.5 V		1.65		1.65	
٧ <sub>I</sub>	Input voltage	-	0	Vcc	0	Vcc	V
۷o	Output voltage		<b>Q</b>	VCC	0	VCC	V
		V <sub>CC</sub> = 3 V	200	-12		-12	
lOH	High-level output current	V <sub>CC</sub> = 4.5 V	A	-24		-24	mA
		V <sub>CC</sub> = 5.5 V		-24		-24	
		V <sub>CC</sub> = 3 V		12		12	
lOL	Low-level output current	V <sub>CC</sub> = 4.5 V		24		24	mA
		V <sub>CC</sub> = 5.5 V		24		24	
Δt/Δν	Input transition rise or fall rate		0	8	0	8	ns/V
T <sub>A</sub>	Operating free-air temperature		-55	125	-40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	Vaa	T,	T <sub>A</sub> = 25°C			C534	SN74A	UNIT	
PARAMETER	TEST CONDITIONS	Vcc	MIN	TYP N	IAX	MIN	MAX	MIN	MAX	UNII
		3 V	2.9			2.9		2.9		
	I <sub>OH</sub> = -50 μA	4.5 V	4.4			4.4		4.4		
Vou		5.5 V	5.4			5.4		5.4		V
VOH	I <sub>OH</sub> = -12 mA	3 V	2.56			2.4		2.46		V
	1011 - 24 mA	4.5 V	3.86			3.7	, S	3.76		
	I <sub>OH</sub> = -24 mA	5.5 V	4.86			4.7	, N	4.76		
	I <sub>OL</sub> = 50 μA	3 V			0.1		0.1		0.1	V
		4.5 V			0.1	4	0.1		0.1	
\/o.		5.5 V			0.1	377	0.1		0.1	
VOL	I <sub>OL</sub> = 12 mA	3 V		(	0.36	0	0.5		0.44	V
	lo: - 24 mA	4.5 V		(	0.36	ď	0.5		0.44	
	$I_{OL} = 24 \text{ mA}$	5.5 V		(	0.36		0.5		0.44	
loz	$V_O = V_{CC}$ or GND	5.5 V		4	±0.5		±5		±2.5	μΑ
lį	V <sub>I</sub> = V <sub>CC</sub> or GND	5.5 V		4	±0.1		±1		±1	μΑ
lcc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			4		80		40	μΑ
Ci	V <sub>I</sub> = V <sub>CC</sub> or GND	5 V		4.5						pF

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### timing requirements over recommended operating free-air temperature range, $V_{CC}$ = 3.3 V $\pm$ 0.3 V (unless otherwise noted) (see Figure 1)

		T <sub>A</sub> = 25°C		SN54AC534 SN74AC534		C534	UNIT	
		MIN	MAX	MIN	MAX	MIN	MAX	UNIT
t <sub>W</sub>	Pulse duration, CLK high or low	5		85	EN	6.5		ns
t <sub>su</sub>	Setup time, data before CLK↑	5		8	c'h	6.5		ns
t <sub>h</sub>	Hold time, data after CLK↑	1		30		1.5		ns

### timing requirements over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

		T <sub>A</sub> = 25°C		SN54AC534		SN74AC534		UNIT
		MIN	MAX	MIN 🙏	MAX	MIN	MAX	UNIT
t <sub>W</sub>	Pulse duration, CLK high or low	3.5		5.5	EV	4		ns
t <sub>su</sub>	Setup time, data before CLK↑	3.5		5.5	7	4		ns
t <sub>h</sub>	Hold time, data after CLK↑	1		2 32		1.5		ns

# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 3.3 V $\pm$ 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T <sub>A</sub> = 2	25°C	SN54A	C534	SN74A	C534	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	MAX	MIN	MAX	MIN	MAX	UNII
f <sub>max</sub>			70		60	1	70		MHz
t <sub>PLH</sub>	CLK	Ια	3	14	2	17.5	2.5	16	ns
t <sub>PHL</sub>	CLK	Q	3	13	2	16.5	2.5	15	115
<sup>t</sup> PZH	ŌĒ	Ια	3	12.5	2	15.5	2.5	14	ns
t <sub>PZL</sub>	OE	Q [	3	12.5	3	15.5	2.5	14	115
<sup>t</sup> PHZ	ŌĒ	Iα	2	13.5	0 1	16.5	1.5	15	ns
t <sub>PLZ</sub>	OL	ά	2	12	Q 1	15	1.5	13.5	115

# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

DADAMETED	FROM	то	T <sub>A</sub> = :	25°C	SN54A	C534	SN74A	C534	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
f <sub>max</sub>			150		75	Į.	140		MHz
<sup>t</sup> PLH	CLK	_	2.5	10.5	1.5	13.5	2	12	200
<sup>t</sup> PHL	CLK	Q	2.5	9.5	1.5	12.5	2	11	ns
<sup>t</sup> PZH	<del>OE</del>	_	2.5	10	1.5	13	2	11.5	ns
t <sub>PZL</sub>	OE	Q	2.5	10	1.5	13	2	11.5	115
<sup>t</sup> PHZ	<del>OE</del>	Q	1.5	11.5	0 1	14	1	12.5	ns
t <sub>PLZ</sub>		~	1.5	10	Q 1	12.5	1	11	115

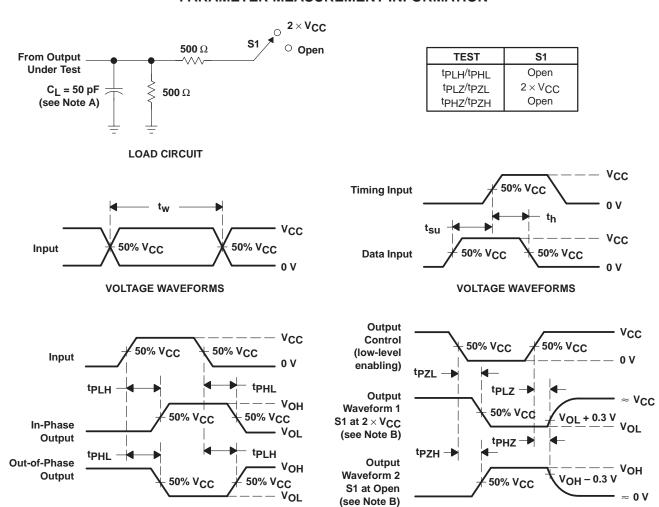
### operating characteristics, $V_{CC} = 5 \text{ V}$ , $T_A = 25^{\circ}\text{C}$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub>	Power dissipation capacitance	$C_L = 50 \text{ pF}, f = 1 \text{ MHz}$	40	pF

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**VOLTAGE WAVEFORMS** 

#### PARAMETER MEASUREMENT INFORMATION



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

**VOLTAGE WAVEFORMS** 

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \Omega$ ,  $t_f \leq$  2.5 ns,  $t_f \leq$  2.5 ns.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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